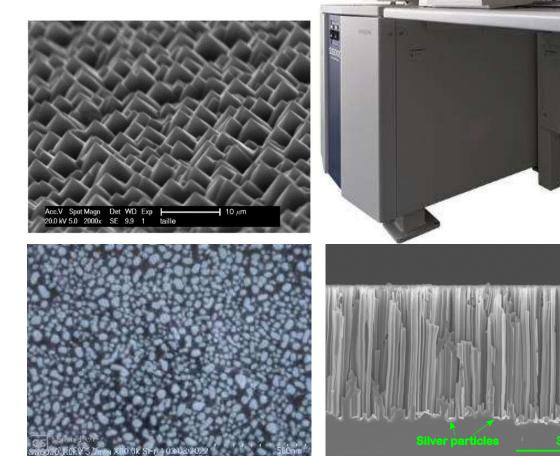
RUTGERS

Scanning Electron Microscope with EDX – Hitachi SU5000

- Analyze defects, features and structures at micro and nanoscale
- Emitter: ZrO / W Schottky emitter
- Voltage: 0.5~30 kV (0.1 kV step)
- Resolution:
 - 1.2 nm @ 30 kV
 - 3.0 nm @ 1 kV
- Specimen Size:
 - up to 200 mm ϕ
 - 80mm in height
- Movement:
 - X= 0~100 mm
 - $Y = 0 \sim 50 \text{ mm}$
 - Z = 3~65 mm
 - T = -20~90 °
 - R = 360 °



Nanofabrication CORE Facility